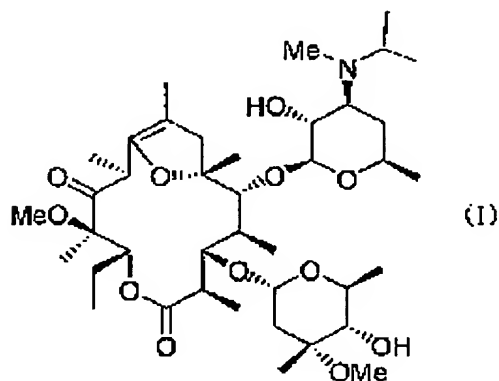


This listing of claims will replace all prior versions, and listings, of claims in the application:

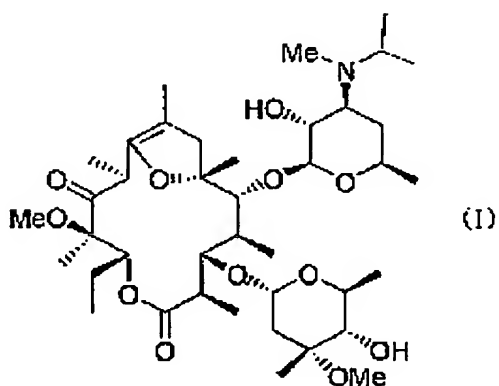
Listing of Claims:

1. (Original) A hemifumarate crystal of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°.

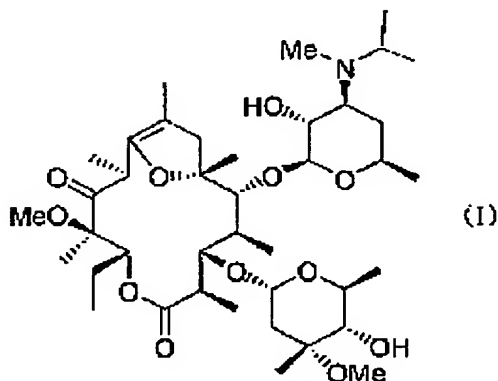
2. (Original) A hemifumarate anhydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray

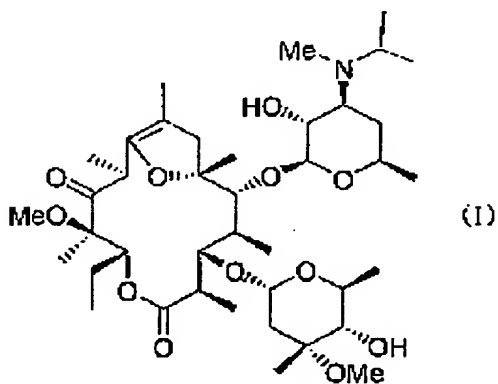
diffraction pattern of  $7.1^\circ$ ,  $13.5^\circ$  and  $14.2^\circ$ .

3. (Original) A hemifumarate X-hydrate of a compound of formula (I):



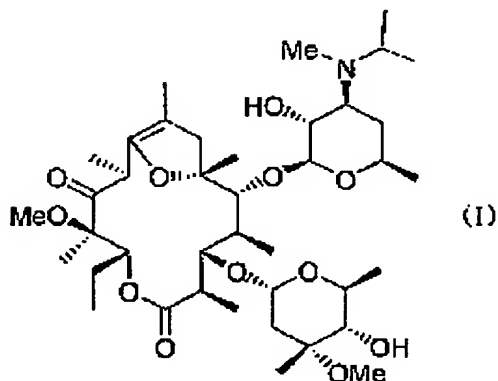
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$  and  $14.2^\circ$ .

4. (Original) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



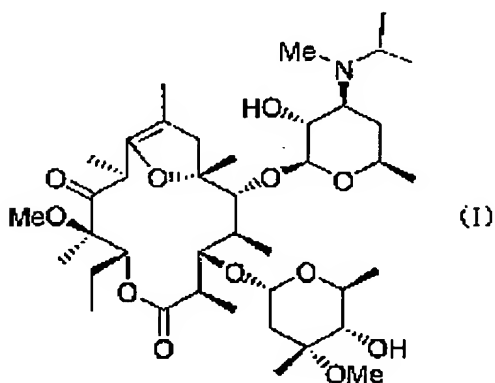
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$ , said process comprising the step of treating a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$ ,  $13.5^\circ$  and  $14.2^\circ$ , to obtain said hemifumarate X-hydrate.

5. (Original) A process for preparing a hemifumarate anhydrate of a compound of formula (I):



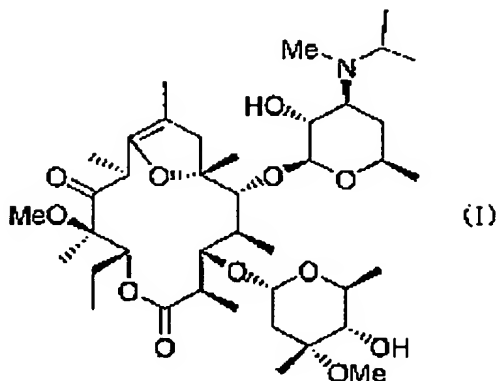
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, said process comprising the step of treating a hemifumarate crystal form of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 6.6° and 8.5°, to obtain said hydrate.

6. (Original) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



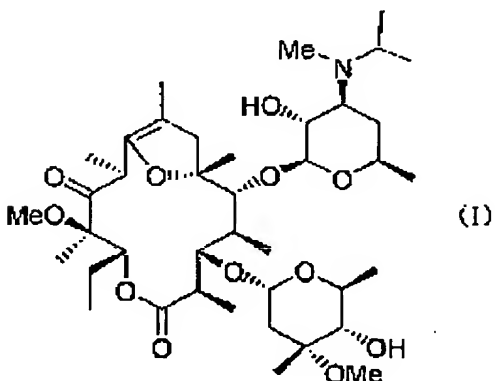
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1° and 14.2°, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) 6.6° and 8.5°, to obtain said hydrate.

7. (Original) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$  and  $14.2^\circ$ , said process comprising the step of treating a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$ ,  $13.5^\circ$  and  $14.2^\circ$ , wherein said hemifumarate anhydrate is obtained by treating a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $6.6^\circ$  and  $8.5^\circ$ .

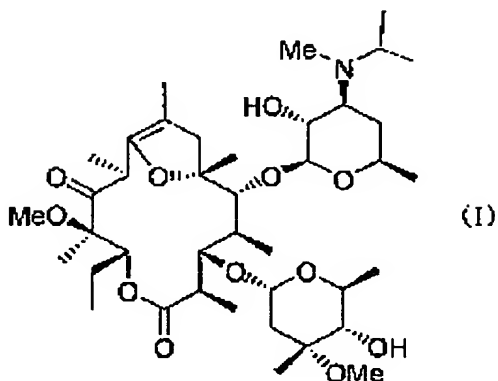
8. (Original) A hemifumarate crystal of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray

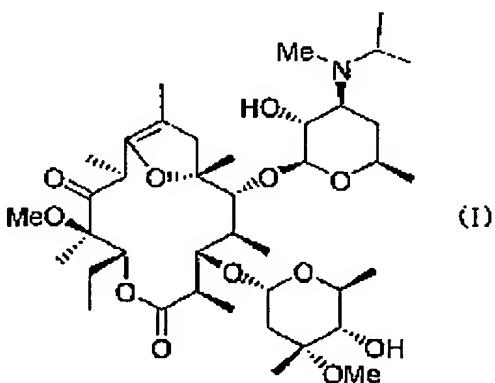
diffraction pattern of  $5.4^\circ$ ,  $10.4^\circ$ ,  $10.7^\circ$  and  $12.1^\circ$ .

9. (Original) A hemifumarate crystal of a compound of formula (I):



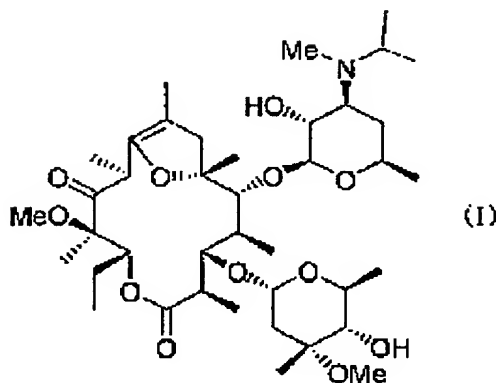
containing acetone and showing strong X-ray diffraction peaks at diffraction angles  $2\theta = 5.4^\circ$ ,  $10.4^\circ$ ,  $10.7^\circ$  and  $12.1^\circ$  measured by X-ray diffractometry using Cu-K $\alpha$  radiation.

10. (Original) A hemifumarate crystal of a compound of formula (I):



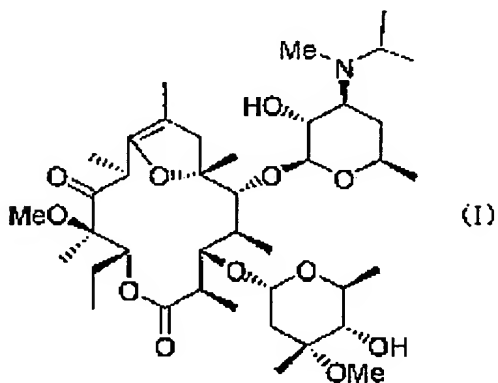
containing methylethylketone and showing strong X-ray diffraction peaks at diffraction angles  $2\theta = 5.4^\circ$ ,  $10.4^\circ$ ,  $10.7^\circ$  and  $12.1^\circ$  measured by X-ray diffractometry using Cu-K $\alpha$  radiation

11. (Original) A hemifumarate crystal of a compound of formula (I):



containing tetrahydrofuran and showing strong X-ray diffraction peaks at diffraction angles  $2\theta = 5.4^\circ$ ,  $10.4^\circ$ ,  $10.7^\circ$  and  $12.1^\circ$  measured by X-ray diffractometry using Cu-K $\alpha$  radiation.

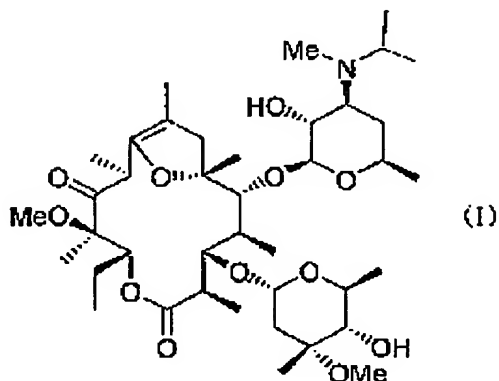
12. (Previously Presented) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



showing strong X-ray diffraction peaks at diffraction angles  $2\theta = 5.4^\circ$ ,  $10.4^\circ$ ,  $10.7^\circ$  and  $12.1^\circ$  measured by X-ray diffractometry using Cu-K $\alpha$  radiation, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) characterized by  $2\theta$  angle positions in the powder X-ray diffraction pattern of  $5.4^\circ$ ,  $10.4^\circ$ ,  $10.7^\circ$  and

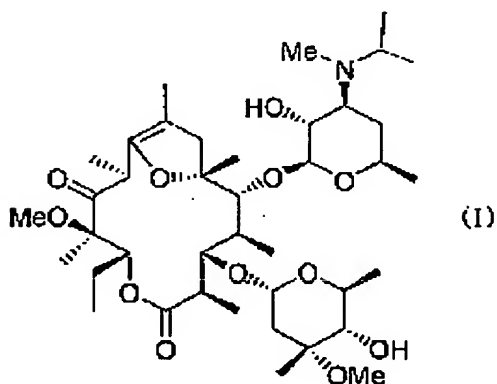
12.1°, to obtain said hydrate.

13. (Previously Presented) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



containing acetone and showing strong X-ray diffraction peaks at diffraction angles  $2\theta = 5.4^\circ$ ,  $10.4^\circ$ ,  $10.7^\circ$  and  $12.1^\circ$  measured by X-ray diffractometry using Cu-K $\alpha$  radiation, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) characterized by  $2\theta$  angle positions in the powder X-ray diffraction pattern of  $5.4^\circ$ ,  $10.4^\circ$ ,  $10.7^\circ$  and  $12.1^\circ$ , to obtain said hydrate.

14. (Original) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):

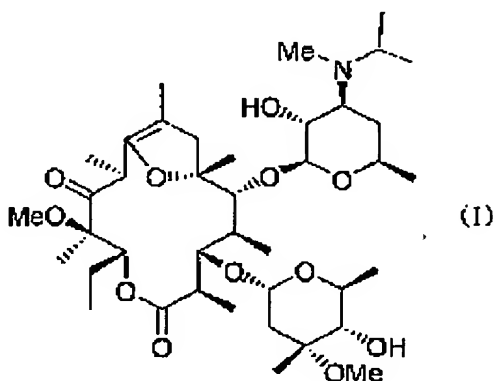


containing methylethylketone and showing strong X-ray diffraction peaks at diffraction angles  $2\theta = 5.4^\circ$ ,  $10.4^\circ$ ,

In re of: KAMADA1

10.7° and 12.1° measured by X-ray diffractometry using Cu-K $\alpha$  radiation, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 5.4°, 10.4°, 10.7° and 12.1°, to obtain said hydrate.

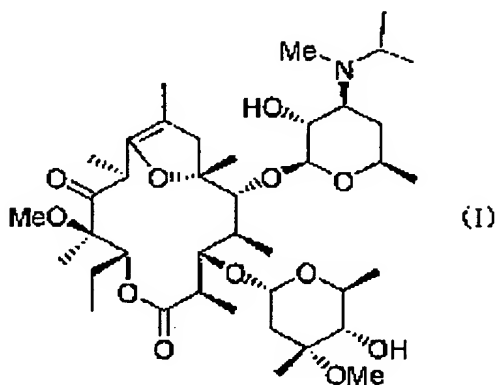
15. (Original) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



containing tetrahydrofuran and showing strong X-ray diffraction peaks at diffraction angles 2 theta = 5.4°, 10.4°, 10.7° and 12.1° measured by X-ray diffractometry using Cu-K $\alpha$  radiation, said process comprising the step of treating a hemifumarate crystal of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 5.4°, 10.4°, 10.7° and 12.1°, to obtain said hydrate.

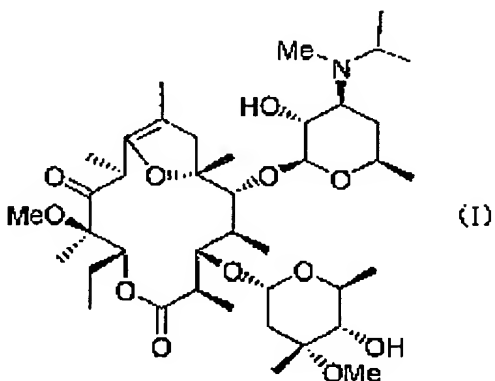


16. (Original) A process for preparing a hemifumarate anhydrate of a compound of formula (I):



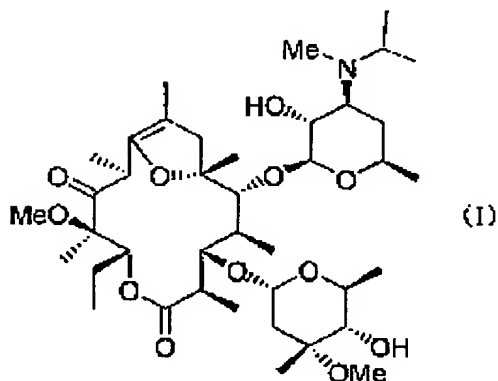
characterized by 2-theta angle positions in the powder X-ray diffraction pattern of 7.1°, 13.5° and 14.2°, said process comprising the step of obtaining said anhydrate by treating a hemifumarate crystal of Claim 8, 9, 10 or 11.

17. (Original) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of showing strong X-ray diffraction peaks at diffraction angles  $2\theta = 7.1^\circ$  and  $14.2^\circ$ , said process comprising the step of obtaining said hydrate by treating a hemifumarate crystal of Claim 8, 9, 10 or 11.

18. (Original) A process for preparing a hemifumarate X-hydrate of a compound of formula (I):



characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$  and  $14.2^\circ$ , said process comprising the step of treating a hemifumarate anhydrate of the compound of formula (I) characterized by 2-theta angle positions in the powder X-ray diffraction pattern of  $7.1^\circ$ ,  $13.5^\circ$  and  $14.2^\circ$ , wherein said anhydrate is obtained by treating a hemifumarate crystal of Claim 8, 9, 10 or 11.